 	Note	-

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/612,615	INOUE ET AL.	
Examiner	Art Unit	
Tianjie Chen	2627	

SEARCHED			
Class	Subclass	Date	Examiner
428	64.4	8/18/2006	ΤJ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Rep[orts	8/18/2006	TJ